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Please replace the first full paragraph beginning on line 6 of page 20, and ending on line 16, page 20, with the following paragraph:

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A<sup>1</sup> Accordingly, in the present invention, dummy conductors disposed in the array direction of conductors are formed in segments so as to prevent any two or more test probes from contacting on one of the dummy conductors simultaneously, and to prevent short circuits between any of the probes resulting from the dummy pattern when the probes are progressively moved in the array direction of conductors for inspection, thereby avoiding erroneous detection and achieving quick and simple determination from the test results whether the conductor pattern is defective or not.

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Please delete the Abstract Section of the specification and replace it with the following abstract in clean form. Applicant includes herewith an Attachment for Specification Amendments showing a marked up version of the previous version of the Abstract Section.

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A<sup>2</sup> A conductor pattern having both elongated conductors and a dummy pattern is formed on a substrate. The dummy pattern is formed of dummy conductors. The elongated conductors are typically transparent electrodes. The dummy pattern is so configured that each of the dummy conductors are mutually set apart with a spacing as appropriate in the extending direction (top-and-bottom direction) and in the array direction (right-and-left direction) of the transparent electrodes to prevent any two inspection probes from contacting a single dummy conductor.

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